CT440/CT440-PDL

OPTICAL COMPONENT TESTER

Compact tester for fast and accurate characterization of passive optical components (MUX/DEMUX, filters, splitters, etc.) and modules (ROADM, WSS). Covers the spectral range from 1240 to 1680 nm for measurements over the full telecom band. With the PDL option, simultaneously measure insertion loss and polarization dependent loss.



KEY FEATURES AND BENEFITS

Fast transfer function measurement	Dynamic range: 65 dB in a single sweep				
Wavelength range: 1240 - 1680 nm (SMF model)	Combines up to four tunable lasers (SMF type) Four internal detectors, expandable with synchronization				
PM and PDL options					
Wavelength resolution: 1 to 250 pm	19-in rack compatible with 1U format				
Wavelength accuracy: +5 pm					



FAST INSERTION LOSS MEASUREMENT

The CT440 features a unique combination of high-speed electronics and optical interferometry. The four integrated detectors allow for the simultaneous measurement of four channels with a 65 dB dynamic range in a single laser sweep. Moreover, ±5 pm wavelength accuracy is achieved at any sweep velocity from 10 nm/s to 100 nm/s, leaving no compromise between measurement speed and accuracy.

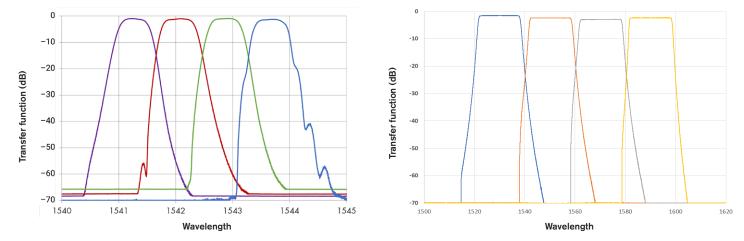


Figure 1. DWDM (left) and CWDM (right) filter measurement in a single sweep

ACCURATE INSERTION LOSS MEASUREMENT

The CT440 integrates a monitoring photodetector to compensate for any power fluctuation coming from the laser source during the sweep. Sampling resolution can be chosen between 1 and 250 pm independently of the laser sweep speed. In addition to the ±5 pm wavelength accuracy, the built-in wavemeter relaxes the requirements for the tunable laser source (TLS) to bring down the system cost without affecting measurement performance. The CT440 provides all the features you need for accurate measurements in a single box when interfaced with a TLS and a PC.

FULL-BAND READY

The CT440 (SMF model) can operate between 1240 and 1680 nm and is fully compatible with EXFO's continuously tunable laser series. For example, combine the T100S-HP-O+, T100S-HP-ES and T100S-HP-CLU with a CT440 SMF model for full-band testing. When several TLSs are used, the CT440 can automatically switch between the lasers to allow for seamless full-band measurements. The single connection to the DUT means no external switch is required.

PM OPTION

The CT440 can be ordered with polarization-maintaining (PM) fiber throughout the instrument as an option. This enables insertion loss characterization of polarization-sensitive components (e.g., MZ modulator), where a polarization maintaining fiber is needed between the TLS input and output ports. Two models cover either the O-band (1260 nm to 1360 nm) with a PM13 fiber type or the SCL-band (1440 nm to 1640 nm) with a PM15 fiber type. As a result, those models require polarization-maintaining tunable lasers, such as the T100S-HP-O-M or T100S-HP-SCL-M, respectively.

PDL OPTION

The CT440-PDL integrates a polarization state generator that allows for spectral characterization of both insertion loss and polarization dependent loss (based on the Mueller matrix method) using successive polarization-controlled sweeps. Two models cover either the O-band (1260 nm to 1360 nm) with a PM13 fibre type or the SCL-band (1440 nm to 1640 nm) with a PM15 fibre type. As a result, these models require polarization-maintaining tunable lasers, such as T100S-HP-O-M or T100S-HP-SCL-M, respectively.

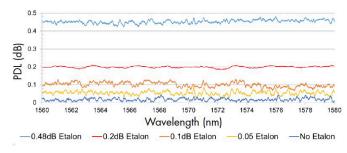


Figure 2. Four PDL etalons measured at 10 pm resolution



Figure 3. CT440-PDL model

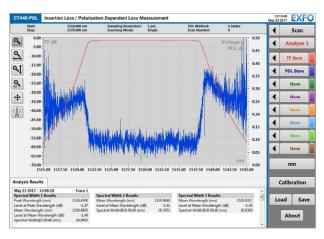


Figure 4. IL and PDL measurement on a CWDM filter

ADDITIONAL FEATURES

Heterodyne detection of laser line (SMF models with ≥2 TLS inputs)

A signal under test (SUT) can be connected to the TLS input n°2. As the laser sweeps across the wavelength range, interference patterns will be generated and detected by the CT440 when it crosses the SUT wavelengths. As such, the CT440 can be used as a multiwavelength meter.

System recalibration using a known reference laser or a fibre-coupled gas cell

For experiments where absolute wavelength referencing is paramount, the CT440 can be used with the wavelength reference material accessories. The wavelength reference material contains either hydrogen fluoride or hydrogen cyanide reference cells exhibiting absorption lines in the O-band and C-band respectively for excellent absolute wavelength accuracy.

Control software with built-in analysis functions

Intuitive and comprehensive GUI for easy laser management, reference and scan configurations and filter analysis.

Full remote control

Thanks to the DLL and the example software code provided with the CT440, component testing can be readily integrated into complex remote control programs.

Optimized form-factor

The CT440 comes in a new rackmountable format (1U in height), ideal for laboratories with limited space.







Figure 5. Rackmountable solution for both (top) CT440 and (bottom) CT440-PDL



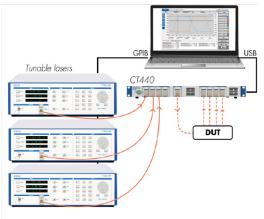
SPECIFICATIONS								
Model	odel			O O-band PM IL	SCL SCL-bands PM IL	PDL-O O-band IL & PDL	PDL-SCL SCL-bands IL & PDL	
Wavelength	Operating wavelength range (nm)		1240 to 1680	1260 to 1360	1440 to 1640	1260 to 1360	1440 to 1640	
	Wavelength	Absolute (pm) a, b	±5					
	accuracy	Relative (pm) ^a	±1 ±5				5	
	TLS inputs and outputs	Number of input ports	1 to 4 (SMF)	1 (PM13)	1 (PM15)	1 (PM13)	1 (PM15)	
		Number of output ports	1 (SMF)	1 (PM13)	1 (PM15)	1 (SMF)		
Ontical parta		Connector type	FC/APC narrow key					
Optical ports (front panel)		Polarization extinction ration (PER)	n/a ≥20 dB ≥18 dB (recommended)			ommended)		
	Detector array	Number of detector ports	1, 2 or 4					
		Connector type	FC/PC wide key					
Electrical ports (rear panel)	Trigger out (5 V	TTL)	Swept measurement external synchronization (pulse train generated at native sampling resolution)					
	Trigger in (5 V TTL)		Triggered measurement without laser sweep control (measurement is taken when TTL level = high)					
	Analog voltage in (0-5 V high impedance)		Voltage level sampling from an external device (sampling resolution of 1.3 mV)					
	D	On TLS input (dBm)			0 to 10			
	Power range	On detector ports (dBm)	-60 to 7					
	Transfer function	Accuracy (dB) c, d	±0.2					
		Sampling resolution (dB)	0.02					
Optical power		Dynamic range ^{d, e}	65 dB typical for 1 or 2 TLS inputs 60 dB typical for 3 or 4 TLS inputs					
	Polarization- dependent	Accuracy (dB) f		n/a ±0.05 + 4% PD		4% PDL		
		Measurement range g	n/a 0 t			20		
	loss	Repeatability	n/a			±0.05		
0	Resolution (pm)		1 to 250 5 to 250					
Sampling characteristics	Native sampling resolution		N x 100 ±10 MHz (N=1 to 250)					
	Compatible sweep speed of TLS (nm/s)		From 10 to 100					
	Interface with Po	C / Data rate	USB-B 2.0 / 4 MBaud					
Data handling	points per TLS p	er of transfer function data er detector as a function of ated detectors by software h	260,000 for 1 detector 219,500 for 2 detectors 164,400 for 3 detectors 131,100 for 4 detectors 110,500 for 5 detectors					
	Temperature	Operating	15 °C to 30 °C (59 °F to 86 °F)					
		Storage	−10 °C to 60 °C (14 °F to 140 °F)					
Environment	Relative humidity		< 80 % non-condensing					
	Power supply		AC 100 V to 240 V (50 Hz to 60 Hz)					
	Dimensions (W x H x D)		440 mm x 50 mm x 375 mm (17.3 in x 2 in x 14.8 in), including rackmounting brackets					
	Weight		Between 3.5 kg and 3.9 kg (7.7 lb to 8.6 lb), depending on model					

MEASUREMENT SETUP				
Tunable laser source (TLS)	Remote control	GPIB		
	Output power	See CT440 specifications above		
	Sweep speed	See CT440 specifications above		
	Mode hops	No mode hop is best but the instrument is able to detect and still operates with a few mode hops		
PC	Operating system	From Windows 7 to Windows 10		
	Interfaces	USB-A 2.0 port to CT440 and GPIB interface card to TLS		

- a. For a TLS sweep > 5 nm at sampling resolution of 5 pm for PDL-0 and PDL-SCL and 1 pm otherwise, excluding the acceleration and deceleration part of the TLS sweep.
- b. After wavelength referencing.
- c. For incident power on detectors > –30 dBm. Accuracy: \pm 0.5 dB for power between –30 dBm and –60 dBm.
- d. 1260 nm to 1640 nm.

- f. For incident power on detectors > -30 dBm and determined from a 6-states measurement at 5 pm resolution.
- g. Stable testing conditions, 6-states recommended for high PDL.
- h. Selected frequency range of the laser divided by the native sampling resolution.





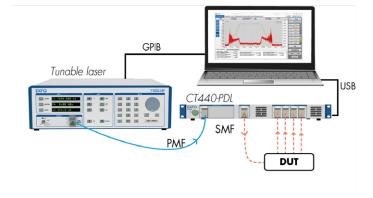
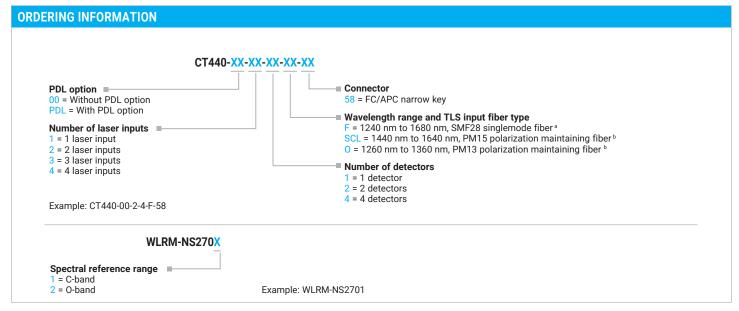


Figure 6. Typical configuration for full band characterization

Figure 7. PDL measurement using the CT440-PDL



- a. Only available only for models without PDL.
- b. Only available with 1 laser input.

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